

P-Channel Enhancement Mode Power MOSFET

Description

The HM2309APR uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge .This device is well suited for use as a load switch or in PWM applications.

General Features

• $V_{DS} = -60V, I_{D} = -5A$

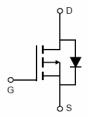
 $R_{DS(ON)}$ <120m Ω @ V_{GS} =-10V

 $R_{DS(ON)}$ <170m Ω @ V_{GS} =-4.5V

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

Application

- Load switch
- PWM application



Schematic diagram



SOT-89 -3L top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM2309APR	HM2309APR	SOT-89-3L	Ø180mm	8 mm	3000 units

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-60	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	-5	А
Pulsed Drain Current	I _{DM}	-15	А
Maximum Power Dissipation	P _D	1.5	W
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 150	°C

Thermal Characteristic

Thermal Resistance, Junction-to-Ambient(Note 2)	$R_{ heta JA}$	83.3	°C/W
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Electrical Characteristics (T_C=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-60 -		-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-60V,V _{GS} =0V	-	-	-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V_{DS} = V_{GS} , I_D =-250 μ A	-1.5	-2.2	-3.0	V
Drain-Source On-State Resistance	5	V _{GS} =-10V, I _D =-5A	-	106	120	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-4.5V, I _D =-3A	-	135	170	mΩ
Forward Transconductance	g FS	V _{DS} =-5V,I _D =-5A	-	10	-	S
Dynamic Characteristics (Note4)	·					
Input Capacitance	C _{lss}	\/ 00\/\/ 0\/	-	930	-	PF
Output Capacitance	Coss	V_{DS} =-30V, V_{GS} =0V, F=1.0MHz	-	85	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.UIVITZ	-	35	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	8	-	nS
Turn-on Rise Time	t _r	V_{DD} =-30V, R_L =7.5 Ω ,	-	4	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =-10 V , R_{G} =3 Ω	-	32	-	nS
Turn-Off Fall Time	t _f		-	7	-	nS
Total Gate Charge	Qg	V 201 5A	-	25	-	nC
Gate-Source Charge	Q _{gs}	V_{DS} =-30, I_{D} =-5A,	-	3	-	nC
Gate-Drain Charge	Q _{gd}	V _{GS} =-10V	-	7	-	nC
Drain-Source Diode Characteristics	- 1					l .
Diode Forward Voltage (Note 3)	V _{SD}	V_{GS} =0 V , I_{S} =-5 A	-		-1.2	V
Diode Forward Current (Note 2)	Is		-	-	-5	Α
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F =- 5A	-	25		nS
Reverse Recovery Charge	Qrr	$di/dt = -100A/\mu s^{(Note3)}$	-	31		nC

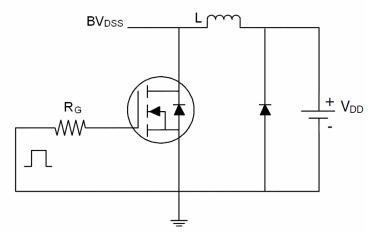
Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production

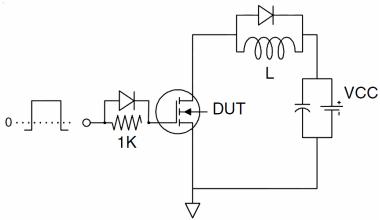


Test Circuit

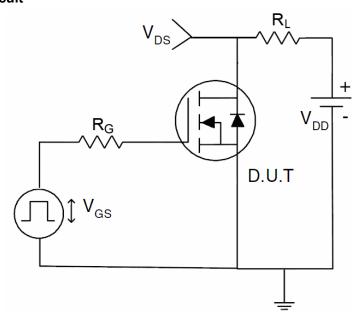
1) E_{AS} test Circuit



2) Gate charge test Circuit

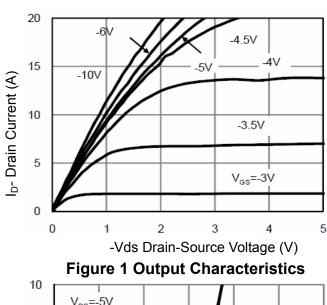


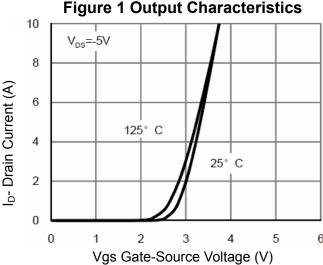
3) Switch Time Test Circuit

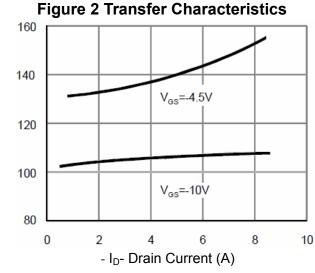




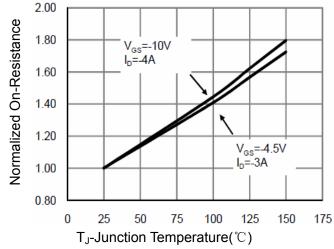
Typical Electrical and Thermal Characteristics (Curves)



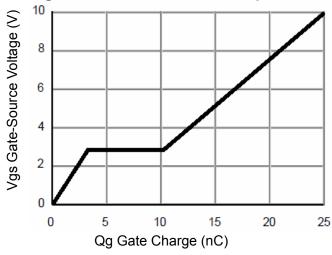












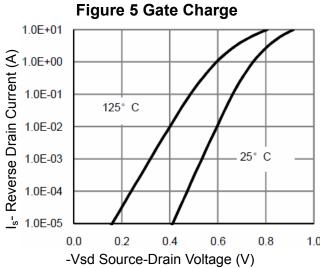


Figure 6 Source- Drain Diode Forward



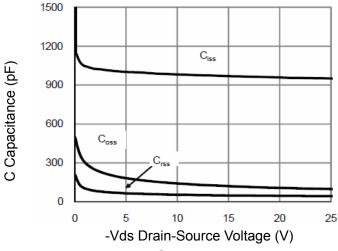


Figure 7 Capacitance vs Vds

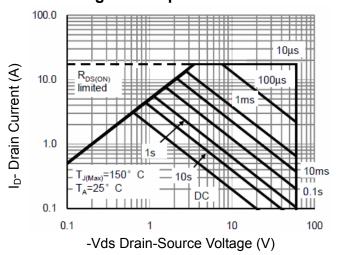


Figure 8 Safe Operation Area

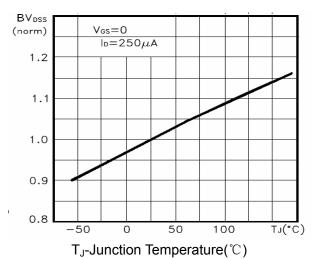


Figure 9 BV_{DSS} vs Junction Temperature

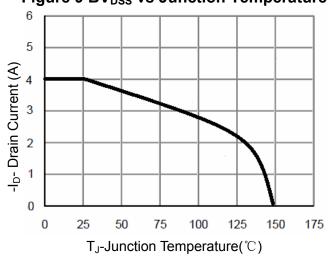
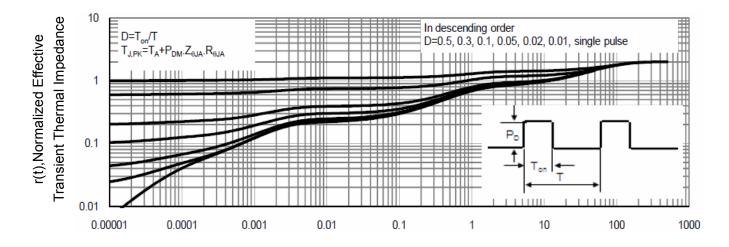


Figure 10 ID Current De-rating

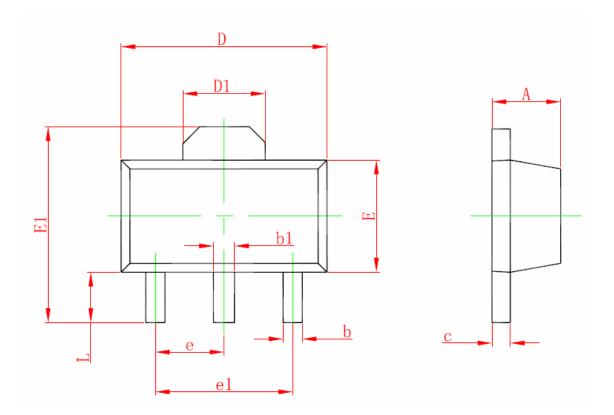


Square Wave Pluse Duration(sec)

Figure 11 Normalized Maximum Transient Thermal Impedance



SOT-89-3L Package Information



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min	Max	Min	Max	
Α	1.400	1.600	0.055	0.063	
b	0.320	0.520	0.013	0.020	
b1	0.400	0.580	0.016	0.023	
С	0.350	0.440	0.014	0.017	
D	4.400	4.600	0.173	0.181	
D1	1.550 REF.		0.061 REF.		
E	2.300	2.600	0.091	0.102	
E1	3.940	4.250	0.155	0.167	
е	1.500 TYP.		0.060 TYP.		
e1	3.000 TYP.		0.118 TYP.		
L	0.900	1.200	0.035	0.047	

Notes

- 1. All dimensions are in millimeters.
- 2. Tolerance ±0.10mm (4 mil) unless otherwise specified
- 3. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 5 mils.
- 4. Dimension L is measured in gauge plane.
- 5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.





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